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Small-Signal MOSFETs

3N128, 3N143

Silicon MOS Transistor

For Amplifier Mixer & Oscillator Applications in Military & Industrial VHF Communications Equipment Operating up to 250 MHz

Features:

- 🛚 Large dynamic range
- Greatly reduces spurious responses in
- receiver front ends Permits use of vacuum-tube biasing
- techniques Excellent thermal stability

Superior crossmodulation capability

Applications:

VHF amplifiers, mixers, converters and if-amplifiers in communication receivers

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- High impedance timing circuits
- Detectors, oscillators, frequency multipliers, phase splitters, pulse stretchers and current limiters
- Electrometer amplifiers
- Voltage-controlled attenuators
- High impedance differential amplifiers

RCA-3N128 and 3N143[•] are N-channel depletion-type silicon field-effect transistors utilizing the MOS construction. The 3N128 is intended primarily for VHF amplifier service in military and industrial applications. It also is extremely well suited for use in dc and low-frequency amplifier applications requiring a transietor bavies high power cain year blob input impedance a transistor having high power gain, very high input impedance, and low gate leakage.

The 3N143 is designed for use as a VHF mixer and oscillator. Because of their improved transfer characteristic and increased dynamic range the 3N128 and 3N143 provide substantially bet ter cross-modulation performance in linear amplifier applications than conventional (bipolar) transistors and are free from diodecurrent loading common to junction type FET's. These transistors are hermetically sealed in JEDEC TO-72 metal packages and utilize full-gate construction.

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Application data for RCA-3N128, including biasing requirements, basic circuit configurations, selection of optimum operating point, and methods for automatic gain control are given in RCA Application Note AN-3193, "Application Con-siderations for the RCA-3N128 VHF MOS Field-Effect Transistor".

Formerly Developmental Nos. TA2840 and TA7275, respectively.

Maximum Ratings, Absolute-Maximum Values: DRAIN-TO-SOURCE VOLTAGE, Vos+20 max. V
GATE-TO-SOURCE VOLTAGE, Ves:
Peak ac±ib inax. v DRAIN CURRENT, I₀ (PULSED)
Peak duration \leq 20 ms, duty factor \leq 0.15TRANSISTOR DISSIPATION, PT:400 mW
TRANSISTOR DISSIPATION, Pr.
AMBIENT TEMPERATURE RANGE: Storage and Operating
LEAD TEMPERATURE (During Soldering): At distances not closer than 1/32 inch to seating surface for 10 seconds maximum

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3N143 MIN TYP

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1014

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3N128, 3N143 T-31-25

MAX

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1,000

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UNITS

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 μ mho

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pF 0.20 0.12

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 μ mho

dB dB

dB

Measured with Substrate Connect		Durce Unless Otherwise Specified.				
CHARACTERISTIC	SYMBOL	CONDITIONS			_	
	511120-		MIN	түр	MAX	M
Forward Transconductance		V _{DS} = 15 V, V _{GS} = 0, f = 1 kHz V _{DS} = 15 V, I _D = 5 mA, f = 1 kHz		10,000 7,500	- 12,000	5,
Magnitude of Forward Transadmittance	Vto	$V_{DS} = 15 V, I_D = 5 mA, f = 200 MHz$	5,000	7,500	•	
Gate Leakage Current	IGSS	$V_{DS} = 0, V_{GS} = -8 \text{ V T}_{A} = 25^{\circ}\text{C}$ $V_{DS} = 0, V_{GS} = -8 \text{ V T}_{A} = 125^{\circ}\text{C}$	•	0.1	50 5	
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Ciss

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R_{GS}

I_D(off)

IDSS

g_{is}

g_{os}

Gps

 $V_{DS} = 15 V$, $I_D = C mA$, f = 0.1 to 1 MHz

V_{DS} = 15 V, 1_D = 5 mA, f = 0.1 to 1 MHz

VDS = 15 V, 1D = 5 mA, f = 0.1 to 1 MHz

 $V_{DS} = 0, V_{GS} = -8 V$

rDS(on) | VDS = 0, VGS = 0, f = 1 kHz

VDS = 20 V VGS = -8 V

 $V_{DS} = 15 V, V_{GS} = 0$

V_{DS} = 15 V, I_D = 5 mA, f = 1 kHz

V_{DS} = 15 V, I_D = 5 mA, f = 1 kHz

VDS = 15V, ID = 5 mA, f = 200 MHz

 $V_{DS} = 15 \text{ V}, \text{ I}_{D} = 1 \text{ mA}, \text{ f}_{in} = 200 \text{ MHz}$

 $V_{GS}(off) | V_{DS} = 15 V, I_D = 50 \mu A$

ELECTRICAL CHARACTERISTICS: (At $T_A = 25^{\circ}$ C)

Small-Signal Short-Circuit Input Capacitance

Small-Signal, Short-Circuit Output Capacitance

Small-Signal Short-Circuit

Gate Leakage Resistance

Gate-to-Source Cutoff Voltage

Drain-to-Source Cutoff Current

Zero-Bias Drain Current**

Power Gain Maximum Available Gain Maximum Usable Gain (Neutralized) see Fig.1

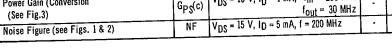
Power Gain (Conversion

Input Conductance

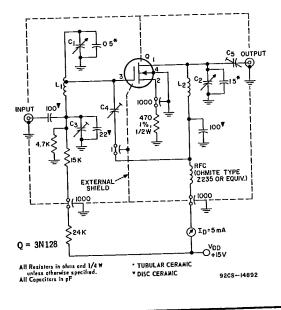
Output Conductance

Reverse Transfer Capacitance*

Drain-to-Source Channel Resistance



* Three-Terminal Measurement: Source Returned to Guard Terminal.



** Pulse Test: Pulse Duration 20 ms max. Duty Factor \leq 0.15.

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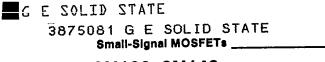
Fig.1 - Test Circuit used to Measure 200 MHz Maximum Usable Power Gain and Noise Figure

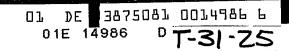
- C1, C2: 1.5-5 pF variable air capacitor: E. F. Johnson Type 160-102 or equivalent
 - C3: 1-10 pF piston-type variable air capacitor: JFD Type VAM-010, Johanson Type 4335, or equivalent
- ${\rm C_4,\ C_5}; \ 0.3\text{-}3\ pF$ piston-type variable air capacitor: Roanwell Type MH-13 or equivalent
 - L1: 5 turns silver-plated 0.02° thick, 0.07°-0.08" wide copper ribbon. Internal diameter of winding = 0.25°; winding length approx. 0.65°. Tapped at 1-1/2 turns from C1 end of winding
 - L2: Same as L_1 except winding length approx. 0.7"; no tap.

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3N128, 3N143

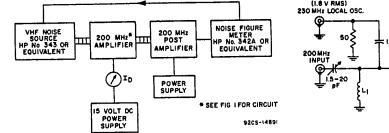


Fig.2 - Noise Figure Measurement Setup for 3N128

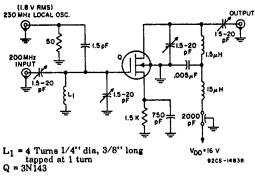
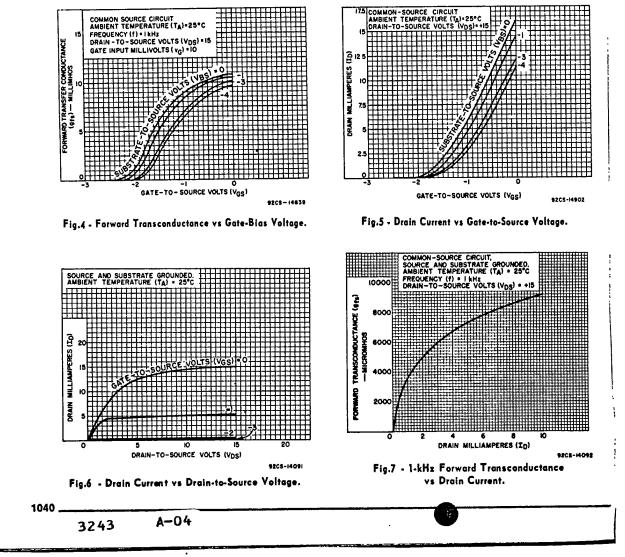
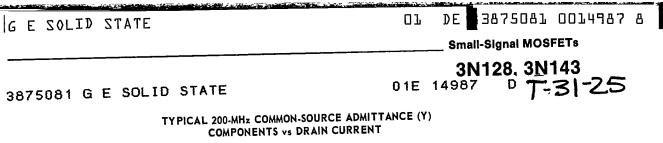


Fig.3 - Conversion Power Gain Test Circuit.





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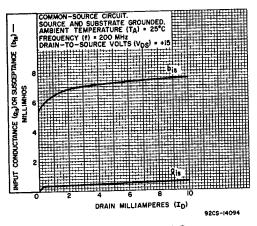


Fig.8 - Input Admittance (Yis) Components.

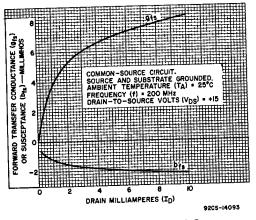


Fig.9 - Forward Transadmittance (Yfs) Components.

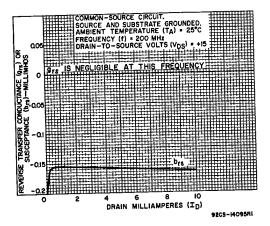


Fig.10 - Reverse Transadmittance (Y_{rs}) Components.

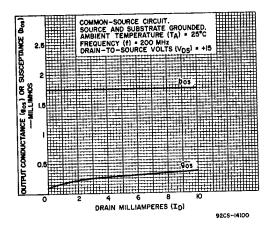


Fig.11 - Output Admittance (Y_{os}) Components.

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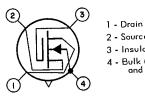
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TERMINAL DIAGRAM



2 - Source 3 - Insulated Gate 4 - Bulk (Substrate) and Case

OPERATING CONSIDERATIONS

The flexible leads of the 3N128 and 3N143 are usually soldered to the circuit elements. As in the case of any high-frequency semiconductor device, the tips of soldering irons should be grounded, and appropriate precautions should be taken to protect the devices against high electric fields.

These devices should not be connected into or disconnected from circuits with the power on because high transient voltages may cause permanent damage to the devices.

